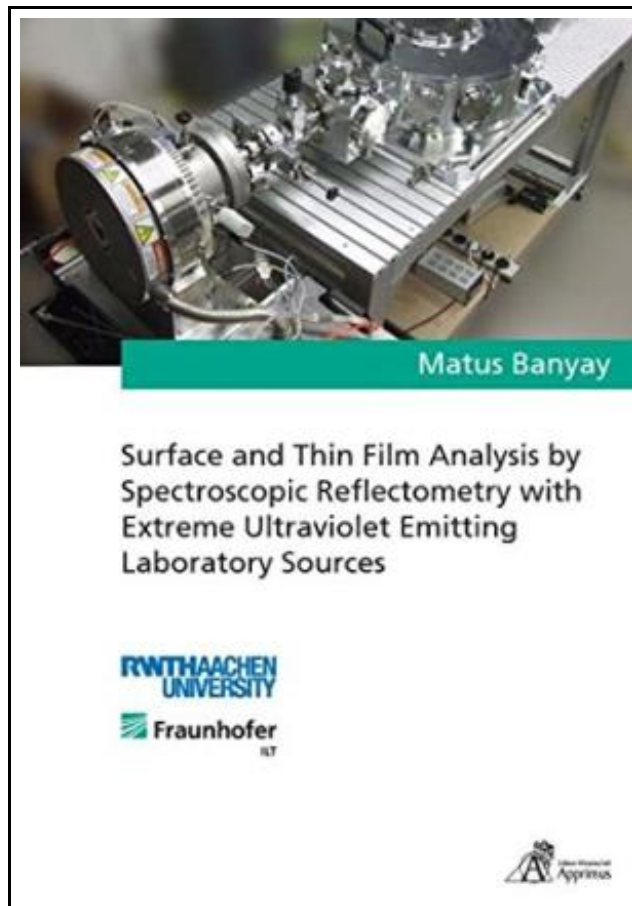


## Surface and Thin Film Analysis by Spectroscopic Reflectometry with Extreme Ultraviolet Emitting Laboratory Sources



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